Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/494,514	NAVEEN ET AL.
Examiner	Art Unit
Michael W. Bowen	2625

SEARCHED					
Class	Subclass	Date	Examiner		
382	305 partial search	7/5/05	MWB		
707	1-7, 104.1 partial	7/06/05	MWB		
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Class & text Search US PAT, US PG-PUB 345/418-475, 581-689 348/445, 556, 571-721, 844, 913 382/108, 155-231, 254-308, 325 706/934 707/1-7, 104.1	6/26/05	MWB	
Search backward citation of USPAT 6,882,746 Naveen Note related application 09/495642	1/5/05	MWB	
Text search: IEEE Xplore ACM	7/6/05	MWB	
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